

<b>Notice of References Cited</b>	Application/Control No. 10/536,716	Applicant(s)/Patent Under Reexamination VERFAILLIE ET AL.	
	Examiner CELINE X. QIAN	Art Unit 1636	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hatada et al (PNAS, December 2000. Vol.97, No.25, pages 13807-13811)
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